

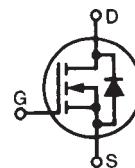
PolarHV™ HiPerFET Power MOSFET ISOPLUS220™

(Electrically Isolated Back Surface)

N-Channel Enhancement Mode

Fast Intrinsic Diode

Avalanche Rated



V_{DSS} = 100 V
 I_{D25} = 60 A
 $R_{DS(on)}$ ≤ 17 mΩ
 t_{rr} ≤ 150 ns

ISOPLUS220™ (IXFC)

E153432



Isolated back surface

G = Gate D = Drain
 S = Source

Features

- | Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- | Low drain to tab capacitance(<35pF)
- | Low $R_{DS(on)}$ HDMOS™ process
- | Rugged polysilicon gate cell structure
- | Unclamped Inductive Switching (UIS) rated
- | Fast intrinsic Rectifier

Applications

- | DC-DC converters
- | Battery chargers
- | Switched-mode and resonant-mode power supplies
- | DC choppers
- | AC motor control

Advantages

- | Easy assembly: no screws, or isolation foils required
- | Space savings
- | High power density
- | Low collector capacitance to ground (low EMI)

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $175^\circ C$	100	V	
V_{DGR}	$T_J = 25^\circ C$ to $175^\circ C$; $R_{GS} = 1 M\Omega$	100	V	
V_{GSS}	Continuous	±20	V	
V_{GSM}	Transient	±30	V	
I_{D25}	$T_c = 25^\circ C$	60	A	
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	250	A	
I_{AR}	$T_c = 25^\circ C$	60	A	
E_{AR}	$T_c = 25^\circ C$	40	mJ	
E_{AS}	$T_c = 25^\circ C$	1.0	J	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 4 \Omega$	10	V/ns	
P_D	$T_c = 25^\circ C$	120	W	
T_J		-55 ... +175	°C	
T_{JM}		175	°C	
T_{stg}		-55 ... +150	°C	
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C	
T_{SOLD}	Plastic body for 10 s	260	°C	
V_{ISOL}	50/60 Hz, RMS t = 1 minute leads-to-tab	2500	V~	
F_c	Mounting Force	11..65 / 2.5..15	N/lb	
Weight		2	g	

Symbol	Test Conditions ($T_J = 25^\circ C$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0 V$, $I_D = 250 \mu A$	100		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 mA$	2.5		5.0 V
I_{GSS}	$V_{GS} = \pm 20 V_{DC}$, $V_{DS} = 0$			±100 nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$			25 μA 250 μA
$R_{DS(on)}$	$V_{GS} = 10 V$, $I_D = 55 A$			17 mΩ

Symbol	Test Conditions	Characteristic Values			
		($T_J = 25^\circ C$, unless otherwise specified)	Min.	Typ.	Max.
g_{fs}	$V_{DS} = 10 V$; $I_D = 55 A$, Note 1	30	43	S	
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 V$, $V_{DS} = 25 V$, $f = 1 MHz$	3550	pF		
		1370	pF		
		440	pF		
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 V$, $V_{DS} = 0.5 V_{DSS}$, $I_D = 60 A$ $R_G = 4 \Omega$ (External)	21	ns		
		25	ns		
		65	ns		
		25	ns		
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 V$, $V_{DS} = 0.5 V_{DSS}$, $I_D = 55 A$	110	nC		
		25	nC		
		62	nC		
R_{thJC}			1.25	$^\circ C/W$	
R_{thcs}		0.21		$^\circ C/W$	

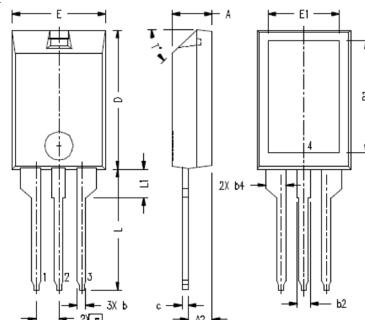
Source-Drain Diode

Characteristic Values
($T_J = 25^\circ C$, unless otherwise specified)

Symbol	Test Conditions	Min.	Typ.	Max.
I_s	$V_{GS} = 0 V$		110	A
I_{SM}	Repetitive		250	A
V_{SD}	$I_F = I_s$, $V_{GS} = 0 V$, Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$		1.5	V
t_{rr} Q_{RM}	$I_F = 25 A$, $-di/dt = 100 A/\mu s$ $V_R = 50 V$, $V_{GS} = 0 V$		150	ns
		0.6		μC

Note: Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$

ISOPLUS220™(IXFC) Outline

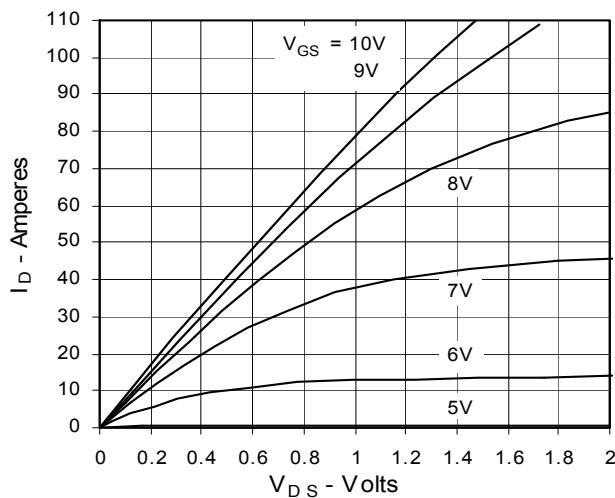


Note:
Bottom heatsink (Pin 4) is electrically isolated from Pin 1,2, or 3.

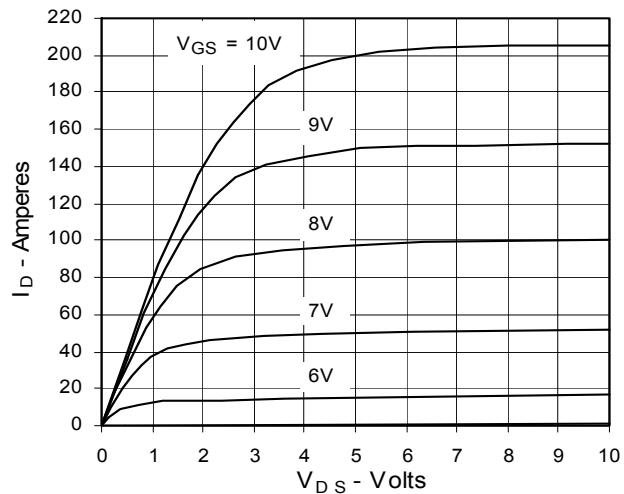
SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.157	.197	4.00	5.00
A2	.098	.118	2.50	3.00
b	.035	.051	0.90	1.30
b2	.049	.065	1.25	1.65
b4	.093	.100	2.35	2.55
c	.028	.039	0.70	1.00
D	.591	.630	15.00	16.00
D1	.472	.512	12.00	13.00
E	.394	.433	10.00	11.00
E1	.295	.335	7.50	8.50
e	.100	BASIC	2.55	BASIC
L	.512	.571	13.00	14.50
L1	.118	.138	3.00	3.50
T*			42.5*	47.5*

Ref: IXYS CO 0177 R0

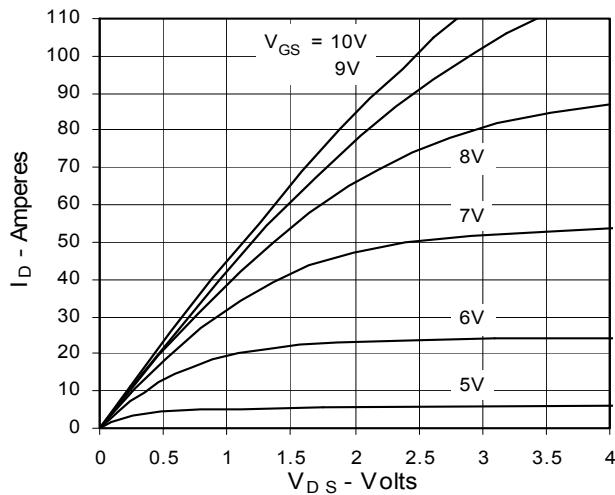
**Fig. 1. Output Characteristics
@ 25°C**



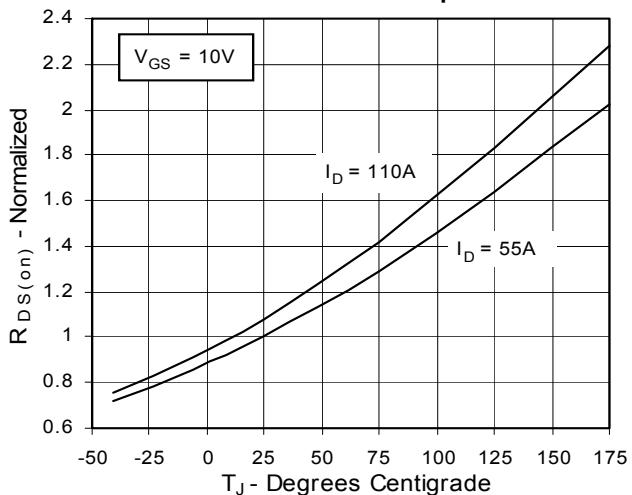
**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 3. Output Characteristics
@ 150°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 55A$
Value vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 55A$
Value vs. Drain Current**

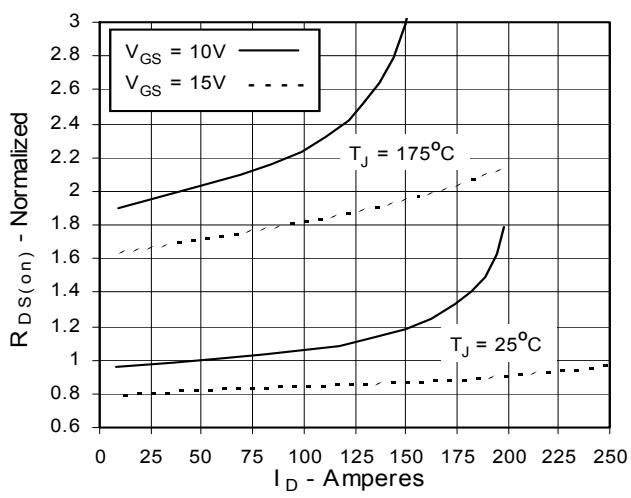


Fig. 6. Drain Current vs. Case Temperature

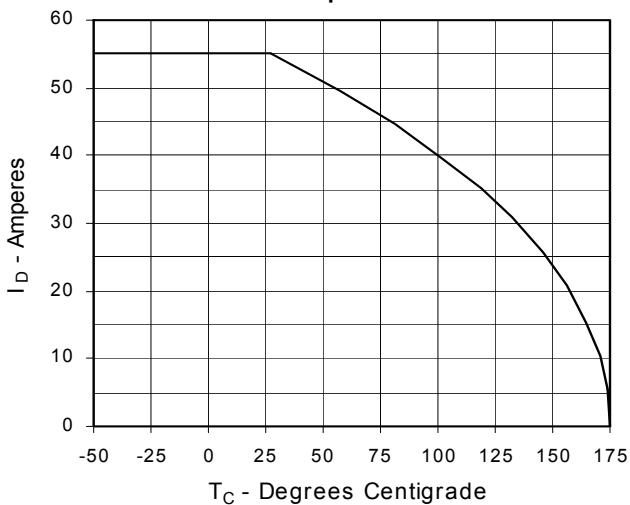


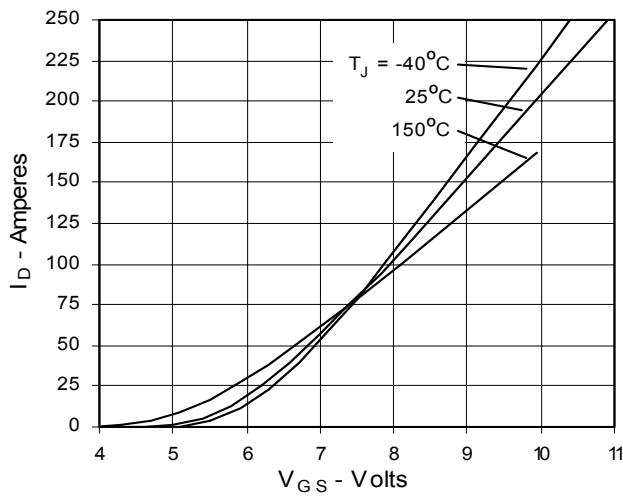
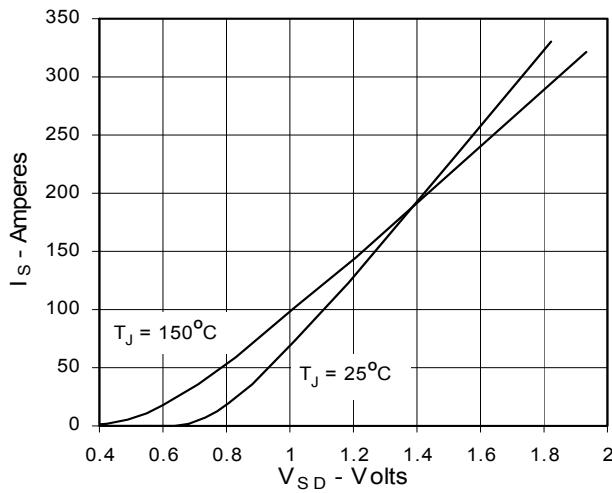
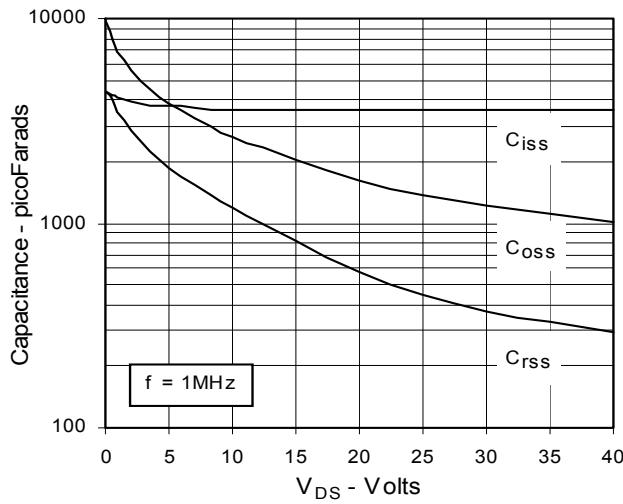
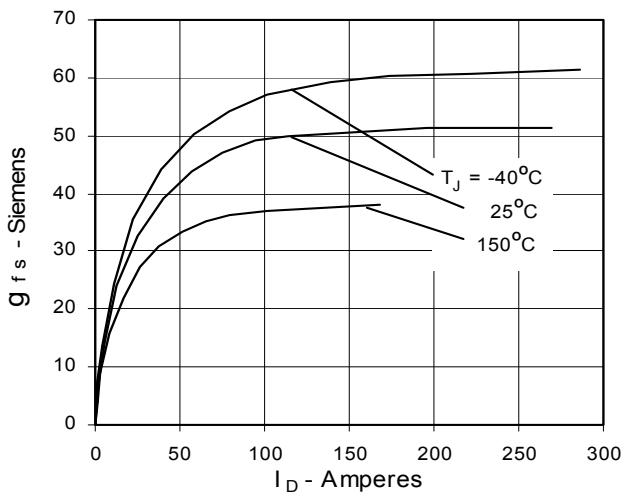
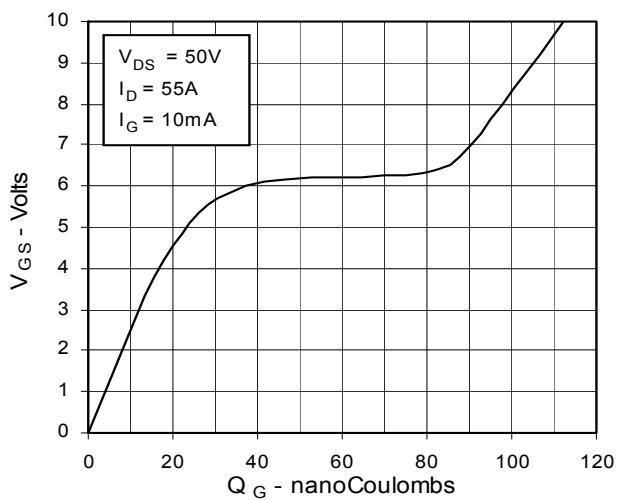
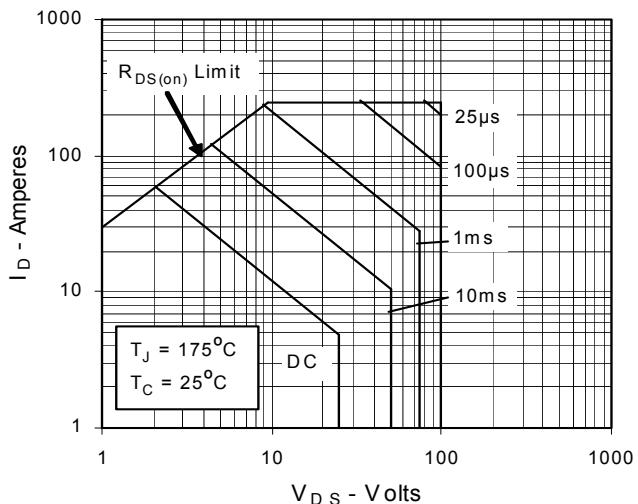
Fig. 7. Input Admittance**Fig. 9. Source Current vs. Source-To-Drain Voltage****Fig. 11. Capacitance****Fig. 8. Transconductance****Fig. 10. Gate Charge****Fig. 12. Forward-Bias Safe Operating Area**

Fig. 13. Maximum Transient Thermal Resistance